

# **:: ASSIGNMENT # 5 ::**

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**Subject: Computer Architecture**

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Q1 Give detail answer to each of the following.

(a) Discuss different types of semiconductor memories in detail.

Types of semiconductor memories.

There are various types of semiconductor memories. The most common is referred to as RAM (Random Access Memory). Most types have the property of Random Access Memory which means that it takes the same amount of time to access any memory location. Below I'll make a table to explain different types of:

Memory type	Category	Access	Write mechanism	Volatility
RAM (Random Access Memory)	Read/Write memory	Electrically Byte level	Electrically	volatile
ROM	Read only memory	Not possible	Masks	Non volatile
PRAM	"	"	"	"
EPROM	"	UV light chip level	"	"
EEPROM	"	Electrically byte level	"	"
Flash Memory	Read Mostly Memory	Electrically block level	Electrically	"

2020-01-10 04:34



(b) Explain the read and write operation for the SRAM. :-

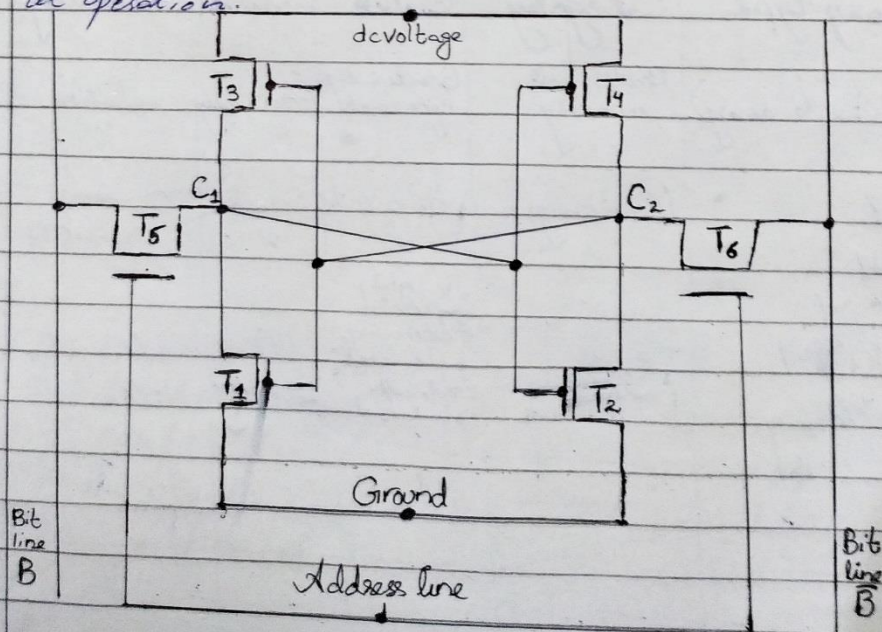
Answer:

Read Operation:

In SRAM, for any operation to be performed the word line should be high. To perform read operations initially, a voltage signal is applied to the bit line. High voltage represents 1, and a low voltage represents 0.

Write Operation:

Consider the memory bits consists of  $Q=0$  and  $Q=1$ . When the address line is selected, the transistor structure and the charge stored on the capacitor is fed out onto a bit line and to a sense amplifier. If the cell contains a logic 1 or a logic 0. The readout from the cell discharges the capacitor, which must be restored to complete the operation.





c) Explain the read and write . . . . .

### Read Operation:

When the address line is selected, the transistor turns on and the charge stored on the capacitor is fed out onto a bitline & to a sense amplifier. It compares the capacitor voltage to a reference value & determines if the cell contains a logic 1 or a logic 0.

### Write operation:

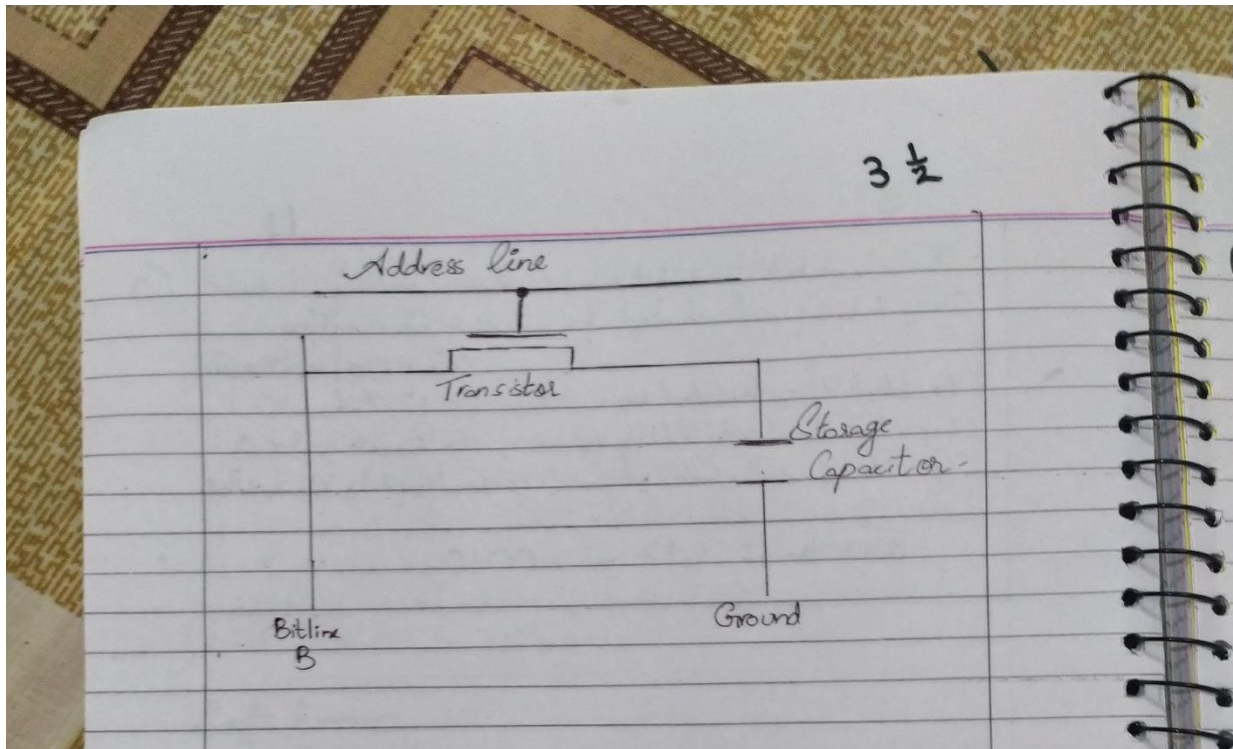
A voltage signal is applied to a bitline a high voltage represents 1 & a low represents 0.

d) Discuss 16.Mbit . . . . .

In the case of this diagram.

- 4 bits are read or written at a time
- Memory array is organized as four arrays of  $2048$  by  $2048$  elements.
- Address lines supply the address of the word to be selected  $\log_2 W$  lines are needed
- These lines are fed into a row decoder
- Decoder activates a single line of memory
- The same procedure is applied to select columns.
- Note that there are ~~only~~ only 11 address lines (A0-A10)
  - Half the number you would expect for a  $2048 \times 2048$  array
- First, a row address select (RAS) signal is emitted

THIS IS THE DIAGRAM OF PART C I FORGOT TO MAKE IT IN START SO MADE IT IN THE END AND INSERTED IT HERE.....





• to define the ~~column~~<sup>row</sup> address of the array.

Second, a column address select (CAS) signal is emitted:

to define the column address of the array.

Write enable (WE) signal

Specifies that a write operation is to be performed.

Output enable (OE) signal.

Signal that specifies that a read operation is to be performed.

Refreshing technique:

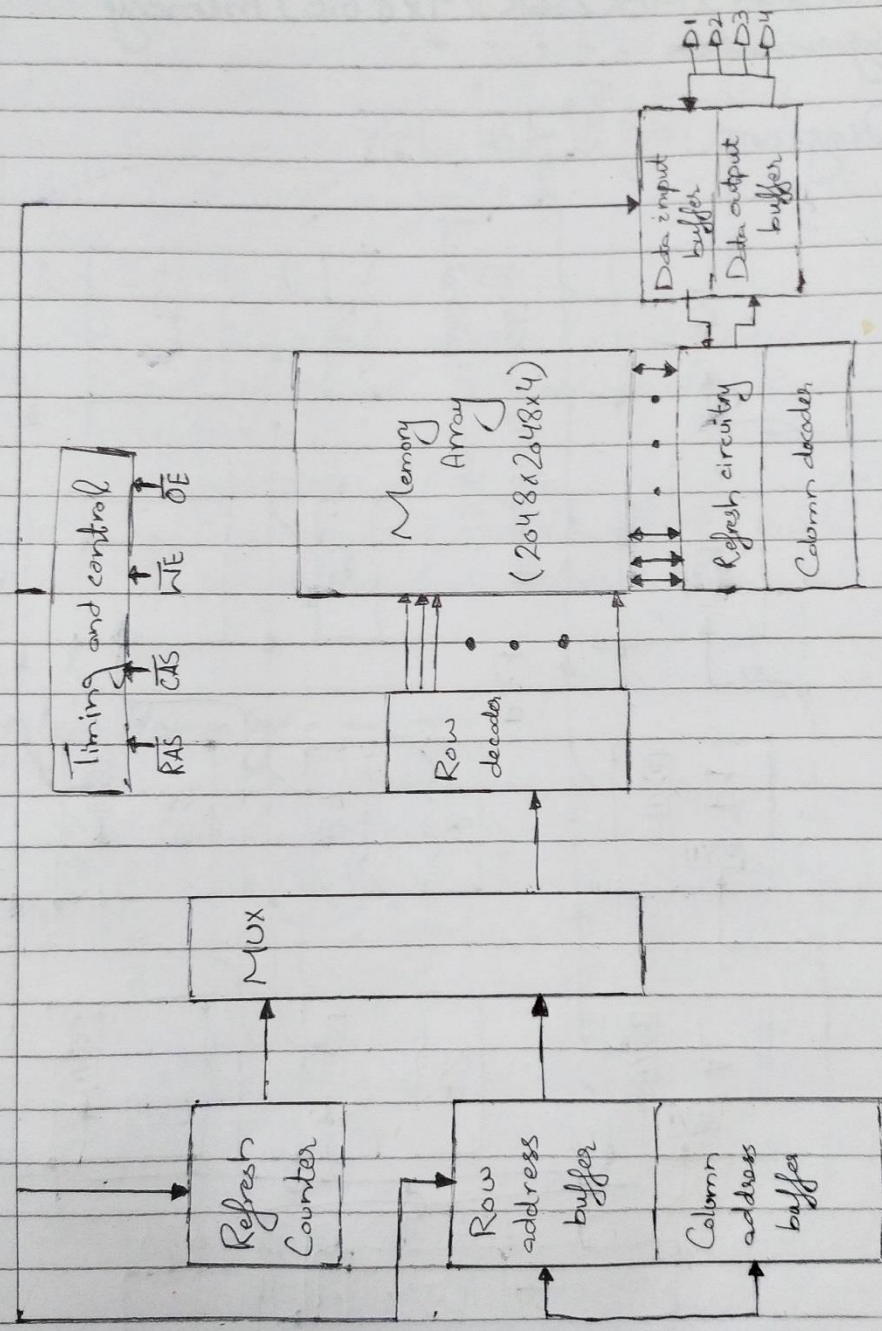
Refresh counter: step through all of the row values.

For each line:

Memory row is chosen, RAS line is activated and Data is read out and written back into the same location.

Disqus

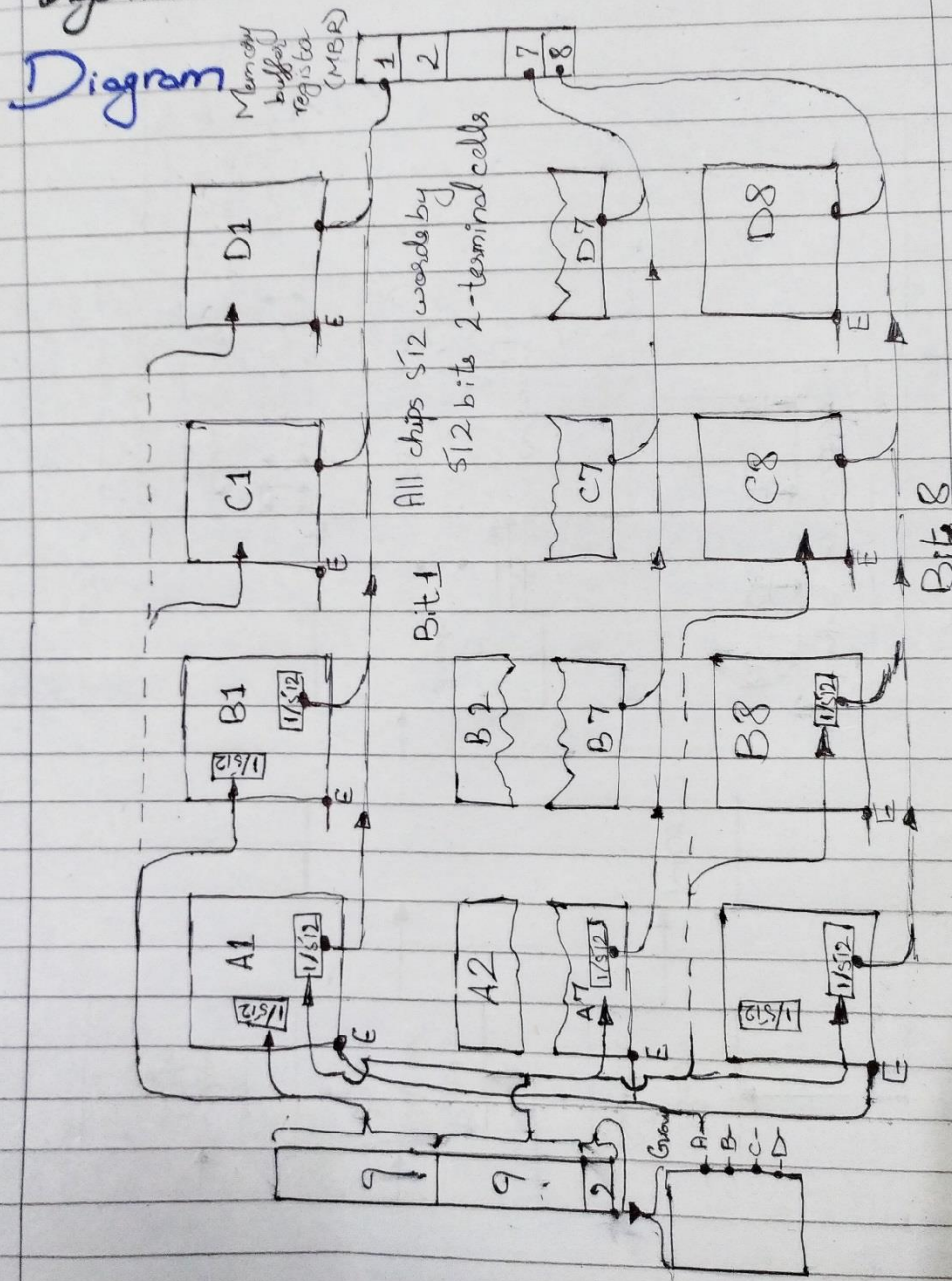
2020/6/10 04:34



5



e) Discuss 1MB (256K x 4 x 8 bit) memory organization . . . . .





Explanation:

$$(1M \times 8bit / 256K \times 8bit) = 4 = 2^2$$

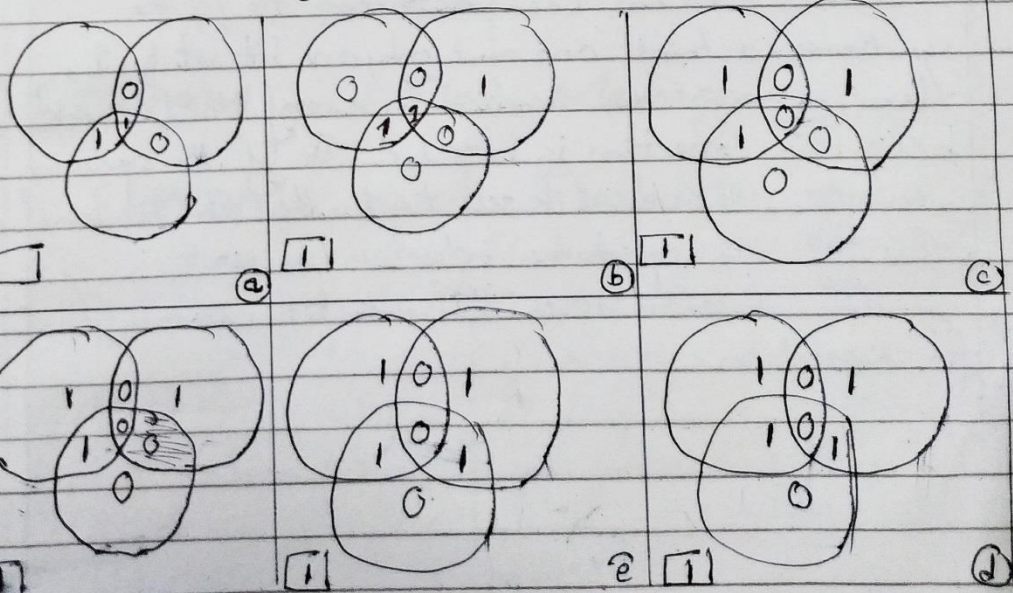
As shown in the figure 1M word by 8bits per word is organized as four columns of chips each column containing 256K words arranged as in prev figure

- $1M = 2^{20}$

For 1M word, 20 address lines are needed. The 18 least significant bits are routed to all 32 modules.

The highest order 2 bits are input to a group select logic module that sends a chip enable signal to one of the four columns of modules.

8) Explain Hamming - - -



2020/6/10 04:34



With 1 bit per chip organization an SEC-DEC code is generally considered adequate e.g. the IBM 30xx implementations used an 8 bit SEC-DEC code for each 64 bits of data in main memory. The size of main memory is actually about 12% larger than is apparent to the user. The VAX computer used a 7 bit SEC-DEC for each 32 bits of memory, for a 22% overhead.

g) How is the syndrome for hamming - - -  
 Answer:

A syndrome is created by the XOR of the code in a word with a calculated version of that code. Each bit of the syndrome is 0 or 1 according to if there is or is not a match in that bit position for the two inputs. If the syndrome contains all 0s, no error has been detected. If the syndrome contains one and only one bit set to 1, then an error has occurred in one of the 4 check bits. No correction is needed. If the syndrome contains more than one bit set to 1, then the numerical value of the syndrome indicates the position of the data bit in error. This data bit is inverted for correction.



Q<sup>2</sup> Differentiate each of the following:

a) DRAM and SRAM:

DRAM	SRAM
<ul style="list-style-type: none"> <li>• DRAM is more dense and less expensive</li> <li>• DRAM requires the supporting refreshing circuitry</li> <li>• DRAM are Normal in speed</li> <li>• DRAM is used for main memory</li> </ul>	<ul style="list-style-type: none"> <li>• SRAM is expensive.</li> <li>• SRAM does not require any refresh circuitry.</li> <li>• SRAM are faster in speed than DRAM</li> <li>• SRAM is used for cache memory.</li> </ul>

b) EEPROM and Flash Memory

EEPROM	Flash Memory
<p>EEPROM devices can erase any byte of memory at any time</p> <p>EEPROM uses NOR type of memory</p> <p>EEPROM is byte wise erasable</p>	<p>Flash memory can only erase an entire chunk or "Sector" of memory at a time.</p> <p>Flash memory uses NAND type memory.</p> <p>Flash is block wise erasable.</p>

2020/6/10 04:34



c) Hard failure and . . . . .

**Hard Failure:**

A hard failure is a permanent physical defect so that the memory cell or cells affected cannot reliably store data but become stuck at 0 or 1 or switch erratically b/w 0 and 1. Hard errors can be caused by harsh ~~error~~ environmental abuse, manufacturing defects and wear.

**Soft Error:**

Soft error is a random, nondestructive event that alters the contents of one or more memory cells without damaging the memory. Soft errors can be caused by power supply problems or alpha particles.

Q<sup>3</sup> Suppose an 8-bit data . . . . .

**Solution.**

Position	12	11	10	9	8	7	6	5	4	3	2	1
Bits	D8	D7	D6	D5	C8	D4	D3	D2	C4	D1	C2	C1
Block	1	0	1	0	-	1	0	1	-	0	-	-
Codes	1100	1011	1010	1001	1000	<del>0111</del> 0111	<del>0110</del> 0110	0101	0100	0011	0010	0001



11

The check bits are in bit numbers 8, 4, 2 and 1  
Check bit 8 calculated by values in bit numbers  
12, 11, 10, and 9 = 0  
Check bit 4 calculated by values in bit 12, 7, 6 and 5 = 1  
Check bit 2 calculated by values in 11, 10, 7, 6 and 3 = 0  
Check bit 1 calculated by values in 11, 9, 7, 5 and 3 = 0

Thus the check bit are = 0010